

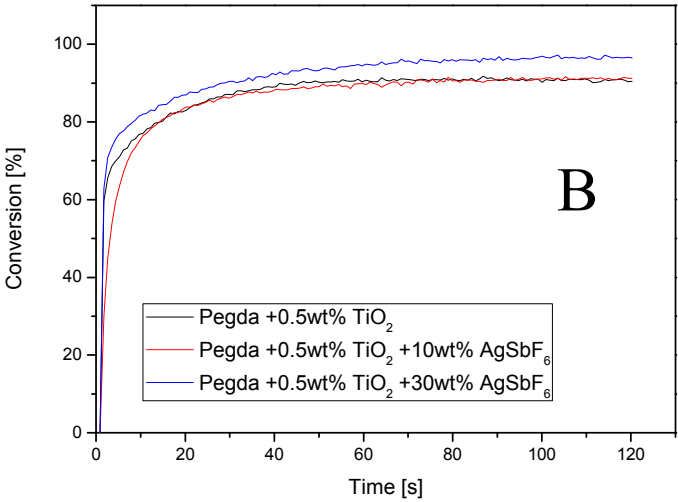
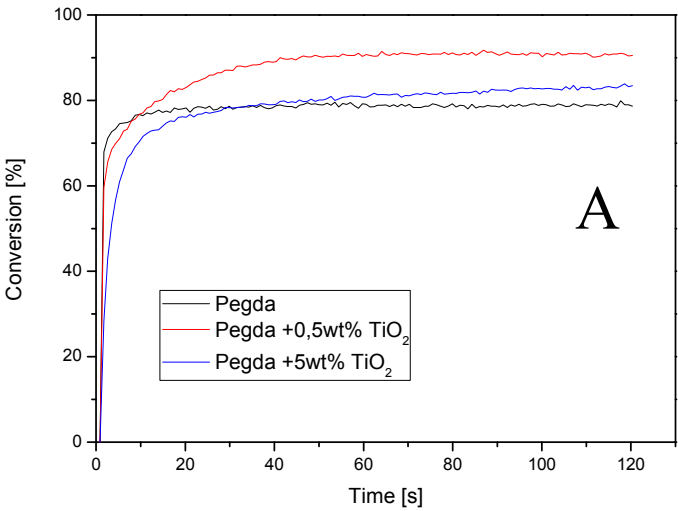
Electronic Supporting Information

Radical diffusion engineering: tailored
nanocomposite materials for piezoresistive inkjet
printed strain sensors

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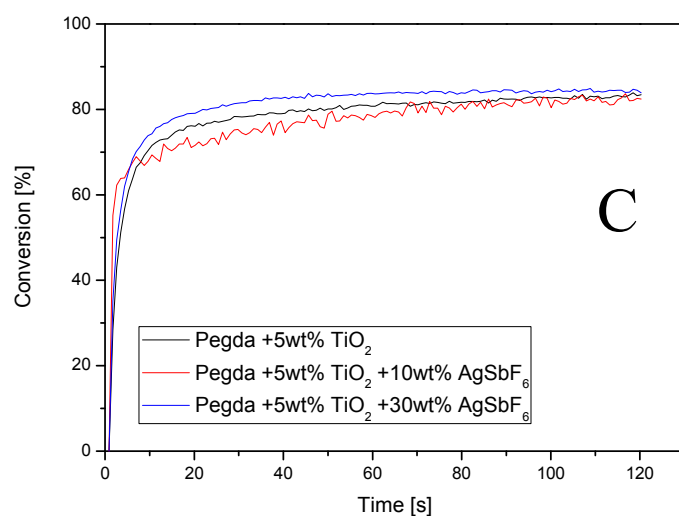


Figure ESI1 Conversion curves for samples: panel a), comparison between the neat formulation and the formulations containing different amount of P25 ; panel b) comparison between formulation containing 0,5wt% of P25 and formulations containing 0,5wt% of P25 with different amount of AgSbF_6 ; panel c), comparison between formulation containing 5wt% of P25 and formulations containing 5wt% of P25 with different amount of AgSbF_6 .

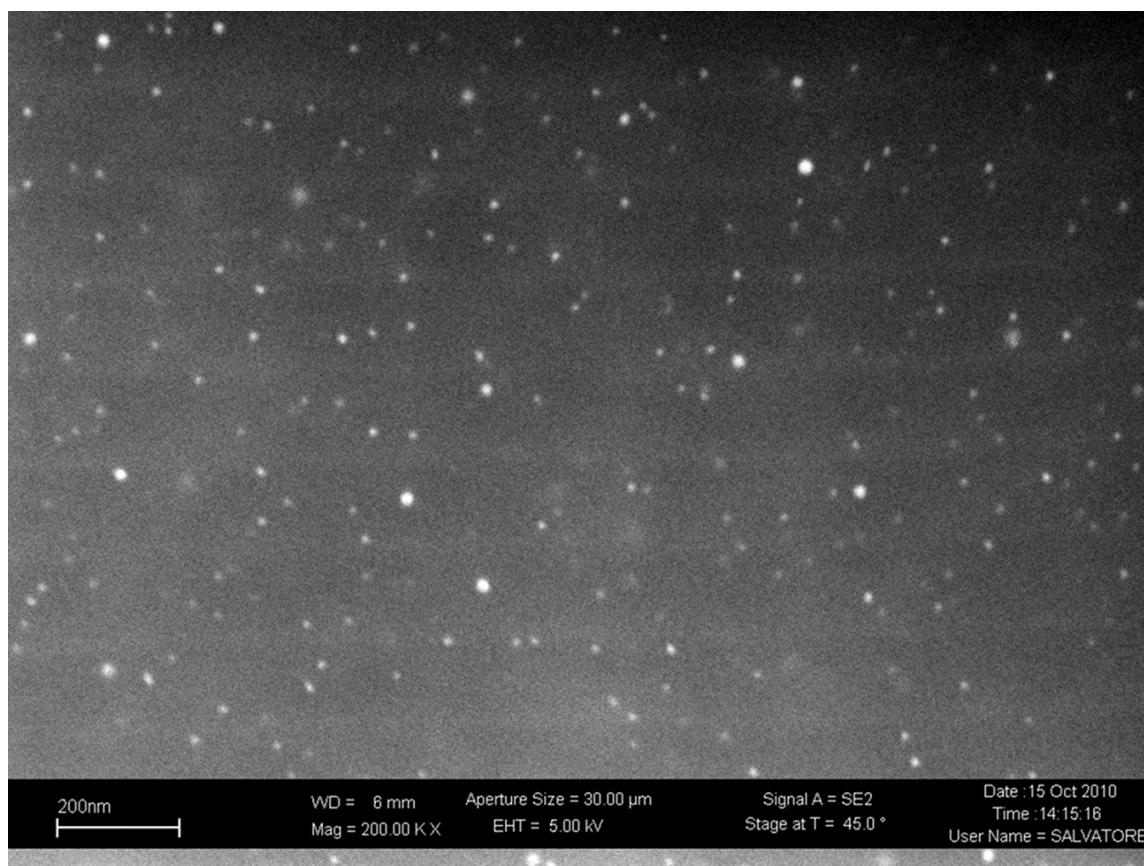


Figure ESI2. FESEM section of a UV cured sample containing 5wt% AgSbF₆.

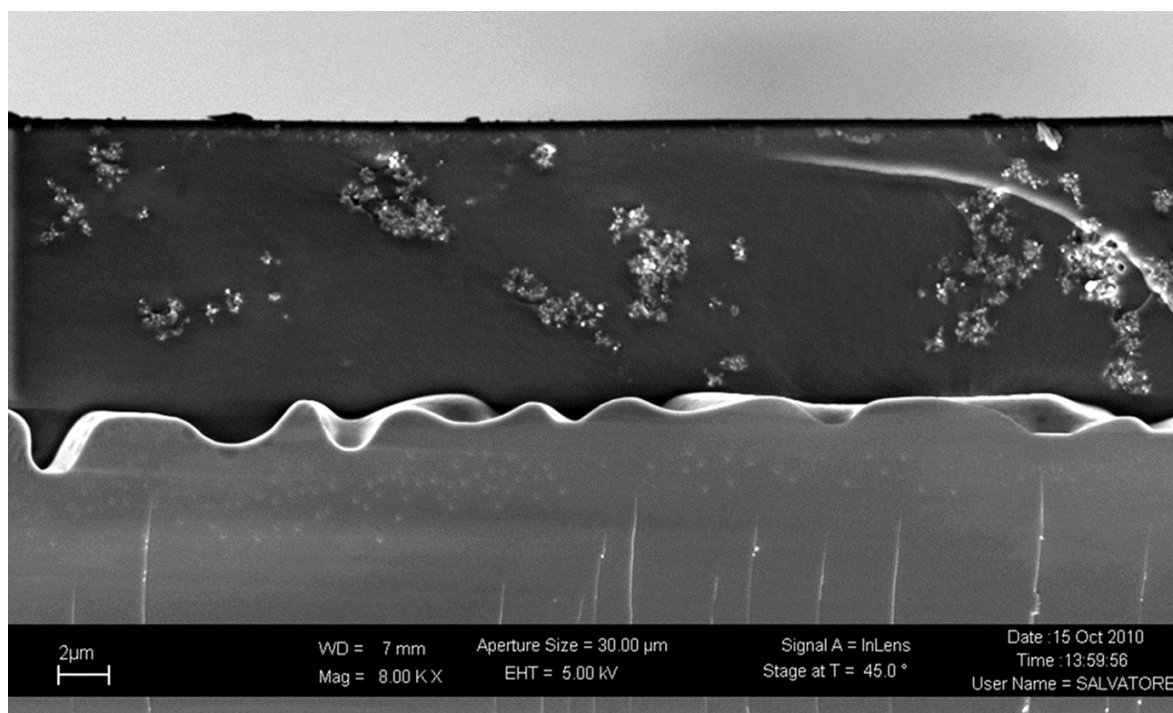


Figure ESI3. FESEM section of a UV cured sample containing 5wt% TiO_2 and 10wt% AgSbF_6 , showing a total thickness around 10 μm . It is possible to see clusters of aggregates of NPs crossing the film section and forming percolative networks.

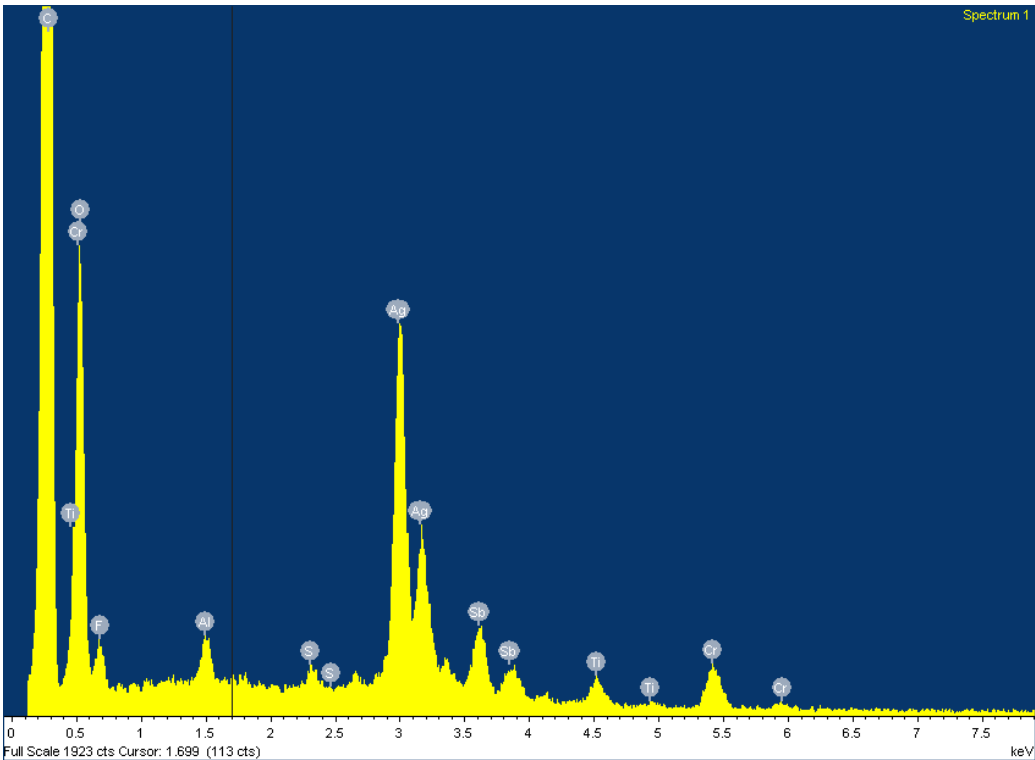


Figure ESI4.EDX spectrum of sample AgSbF₆ 10wt% and TiO₂ 1wt%.

Table ESII1. Composition of sample AgSbF₆ 10wt% and TiO₂ 1wt%, ad determined by EDX quantitative analysis.

Reference line	Apparent Concentration [A.U.]	Intensity Correction [A.U.]	Weight %	Standard Deviation Weight %	Atomic %
C-K	168.48	1.2514	49.41	0.56	64.72
O-K	37.27	0.4570	29.93	0.61	29.43
F-K	1.55	0.1698	3.34	0.48	2.77
Al-K	0.99	0.7994	0.45	0.04	0.26
S-K	0.58	0.9703	0.22	0.04	0.11
Ti-K	1.39	0.7934	0.64	0.06	0.21
Cr-K	3.03	0.8016	1.39	0.08	0.42
Ag-K	26.16	0.8429	11.39	0.24	1.66
Sb-K	6.58	0.7482	3.23	0.15	0.42